

November 2012

FDMS86200

N-Channel Power Trench[®] MOSFET 150 V, 49 A, 18 m Ω

Features

- Max $r_{DS(on)} = 18 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 9.6 \text{ A}$
- Max $r_{DS(on)} = 21 \text{ m}\Omega$ at $V_{GS} = 6 \text{ V}$, $I_D = 8.8 \text{ A}$
- Advanced Package and Silicon combination for low r_{DS(on)} and high efficiency
- MSL1 robust package design
- 100% UIL tested
- RoHS Compliant



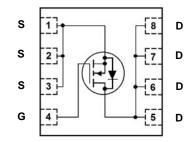
General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced Power Trench® process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

Application

■ DC-DC Conversion





MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parame		Ratings	Units	
V _{DS}	Drain to Source Voltage			150	V
V _{GS}	Gate to Source Voltage			±20	V
	Drain Current -Continuous	T _C = 25 °C		49	
I _D	-Continuous	T _A = 25 °C	(Note 1a)	9.6	Α
	-Pulsed			100	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	220	mJ
D	Power Dissipation	T _C = 25 °C		104	W
P_{D}	Power Dissipation	T _A = 25 °C	(Note 1a)	2.5	VV
T _J , T _{STG}	Operating and Storage Junction Tempera	ature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case		1.2	20044
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS86200	FDMS86200	Power 56	13 "	12 mm	3000 units

Electrical Characteristics T_J = 25 °C unless otherwise noted

Symbol	Parameter	lest Conditions	IVIII	тур	IVIAX	Units
Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	150			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		110		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 120 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2.0	2.5	4.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		-10		mV/°C
		$V_{GS} = 10 \text{ V}, I_D = 9.6 \text{ A}$		15	18	
r _{DS(on)}	r _{DS(on)} Static Drain to Source On Resistance	$V_{GS} = 6 \text{ V}, I_D = 8.8 \text{ A}$		17	21	mΩ
	$V_{GS} = 10 \text{ V}, I_D = 9.6 \text{ A}, T_J = 125 ^{\circ}\text{C}$		28	34		
g _{FS}	Forward Transconductance	$V_{DD} = 10 \text{ V}, I_D = 9.6 \text{ A}$		33		S

Dynamic Characteristics

C _{iss}	Input Capacitance	75 77 77 07	2041	2715	pF
Coss	Output Capacitance	$V_{DS} = 75 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	203	270	pF
C _{rss}	Reverse Transfer Capacitance	1 – 1 1911 12	10	16	pF
R _a	Gate Resistance		1.2	3	Ω

Switching Characteristics

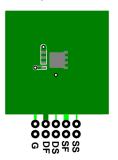
t _{d(on)}	Turn-On Delay Time				13	23	ns
t _r	Rise Time		V _{DD} = 75 V, I _D = 9.6 A,		7.9	16	ns
t _{d(off)}	Turn-Off Delay Time	V _{GS} = 10 V, R _{GEN} :	= 6 Ω		27	44	ns
t _f	Fall Time				5.8	12	ns
0	Total Gate Charge	$V_{GS} = 0 V to 10 V$			33	46	nC
$Q_{g(TOT)}$	Total Gate Charge	$V_{GS} = 0 V to 5 V$	V _{DD} = 75 V		18	26	nC
Q_{gs}	Total Gate Charge		$I_D = 9.6 A$		7.9		nC
Q_{gd}	Gate to Drain "Miller" Charge				7.7		nC

Drain-Source Diode Characteristics

V _{SD} Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 2 \text{ A}$	(Note 2)	0.69	1.2	V	
	$V_{GS} = 0 \text{ V}, I_{S} = 9.6 \text{ A}$	(Note 2)	0.77	1.3	V	
t _{rr}	Reverse Recovery Time	I _F = 9.6 A, di/dt = 100 A/μs		76	120	ns
Q _{rr}	Reverse Recovery Charge			113	181	nC

NOTES

^{1.} R_{BJA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design.



a. 50 °C/W when mounted on a 1 in² pad of 2 oz copper



b.125 °C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300 $\mu s,$ Duty cycle < 2.0 %.
- 3. E_{AS} of 220 mJ is based on starting $T_{J} = 25$ °C, L = 1 mH, $I_{AS} = 21$ A, $V_{DD} = 150$ V, $V_{GS} = 10$ V. 100% test at L = 0.1 mH, $I_{AS} = 46$ A.

Typical Characteristics T_J = 25 °C unless otherwise noted

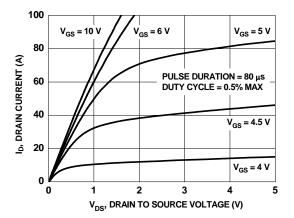


Figure 1. On-Region Characteristics

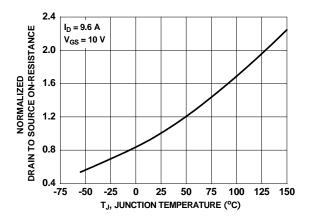


Figure 3. Normalized On-Resistance vs Junction Temperature

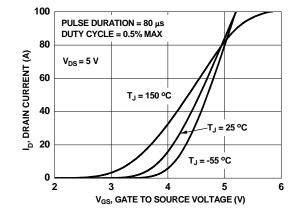


Figure 5. Transfer Characteristics

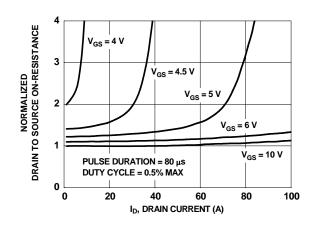


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

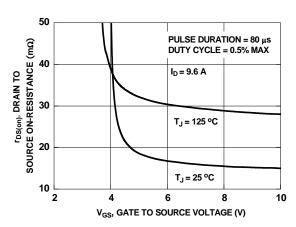


Figure 4. On-Resistance vs Gate to Source Voltage

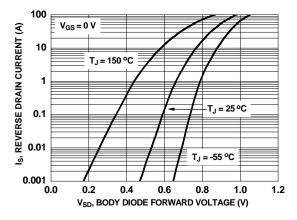


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25$ °C unless otherwise noted

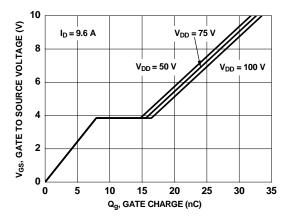


Figure 7. Gate Charge Characteristics

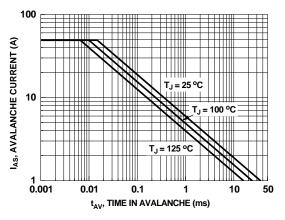


Figure 9. Unclamped Inductive Switching Capability

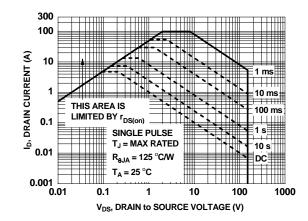


Figure 11. Forward Bias Safe Operating Area

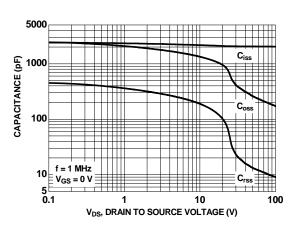


Figure 8. Capacitance vs Drain to Source Voltage

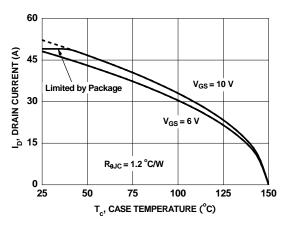


Figure 10. Maximum Continuous Drain Current vs Case Temperature

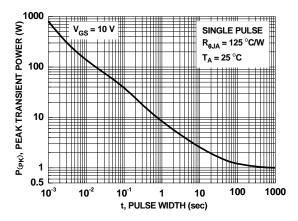


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25 °C unless otherwise noted

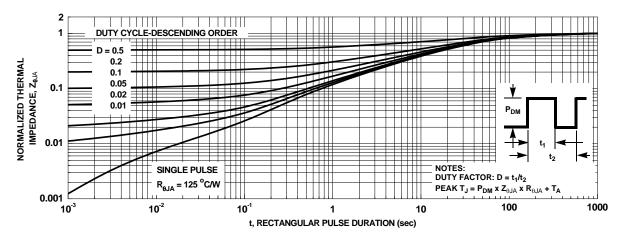
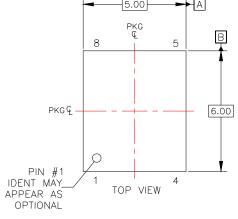
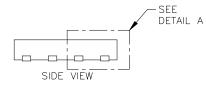
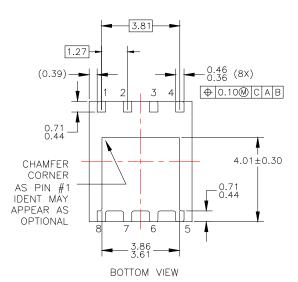


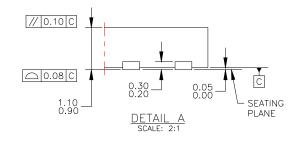
Figure 13. Transient Thermal Response Curve

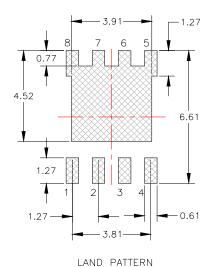
Dimensional Outline and Pad Layout <u></u> ► A 5.00



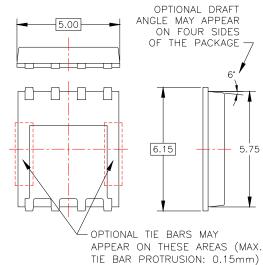












NOTES: UNLESS OTHERWISE SPECIFIED

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